

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/531,208	UEDA ET AL.	
Examiner	Art Unit	
Sin J. Lee	1795	

CEARCHER				
SEARCHED				
Subclass	Date	Examiner		
		SEARCHED Subclass Date		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EIC structure searches (paper nos. 6, 7, 9 and 10) were reviewed.	6/7/2009	SJL